

DARLINGTON POWER TRANSISTOR 2SD2163

NPN SILICON EPITAXIAL TRANSISTOR (DARLINGTON CONNECTION) FOR LOW-FREQUENCY POWER AMPLIFIERS AND LOW-SPEED HIGH-CURRENT SWITCHING

The 2SD2163 is a mold power transistor developed for low-speed high-current switching. This transistor is ideal for direct driving from the IC output of devices such as pulse motor drivers and relay drivers of PC terminals.

FEATURES

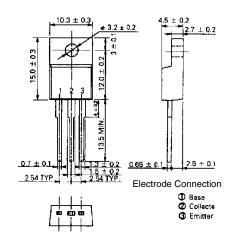
- Mold package that does not require an insulating board or insulation bushing
- High DC current gain due to Darlington connection hfe = 1,000 MIN. (@Ic = 10 A)
- Low collector saturation voltage:
 Vce(sat) = 1.5 V MAX. (@Ic = 10 A)

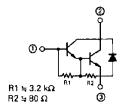
ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

Parameter	Symbol	Ratings	Unit
Collector to base voltage	Vcво	150	V
Collector to emitter voltage	VCEO	100	٧
Emitter to base voltage	V _{EBO}	8.0	٧
Collector current (DC)	Ic(DC)	±10	Α
Collector current (pulse)	Ic(pulse)*	±20	Α
Base current (DC)	I _{B(DC)}	1.0	Α
Total power dissipation	P⊤ (Tc = 25°C)	30	W
Total power dissipation	P⊤ (Ta = 25°C)	2.0	W
Junction temperature	Tj	150	°C
Storage temperature	T _{stg}	-55 to +150	°C

^{*} PW \leq 10 ms, duty cycle \leq 50%

PACKAGE DRAWING (UNIT: mm)





ELECTRICAL CHARACTERISTICS (Ta = 25°C)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Collector cutoff current	Ісво	V _{CB} = 100 V, I _E = 0			10	μΑ
DC current gain	hfe**	Vce = 2.0 V, Ic = 10 A	1,000	6,000	30,000	
Collector saturation voltage	V _{CE(sat)} **	Ic = 10 A, Iв = 25 mA		1.1	1.5	V
Base saturation voltage	V _{BE(sat)} **	Ic = 10 A, Iв = 25 mA		1.8	2.0	V
Turn-on time	ton	$Ic = 10 A$, $I_{B1} = -I_{B2} = 25 \text{ mA}$		1.0		μs
Storage time	tstg	R _L = 5.0 Ω , Vcc \cong 50 V Refer to the test circuit.		5.0		μs
Fall time	tf			2.0		μs

^{**} Pulse test PW ≤ 350 μs, duty cycle ≤ 2%

hfe CLASSIFICATION

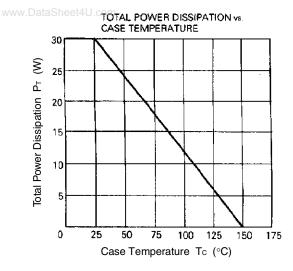
l	Marking	M	L	K	J
	hfE	1,000 to 3,000	2,000 to 5,000	4,000 to 10,000	8,000 to 30,000

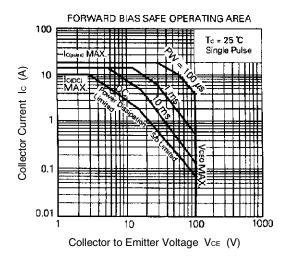
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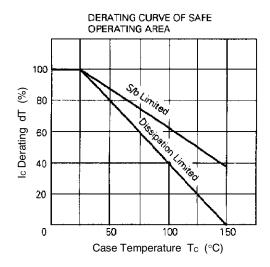
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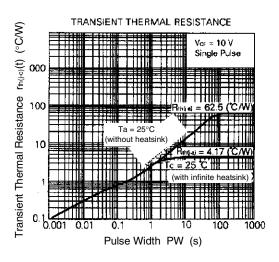


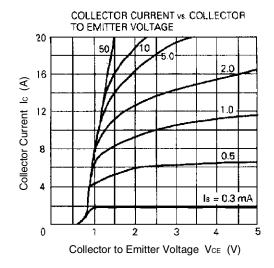
TYPICAL CHARACTERISTICS (Ta = 25°C)

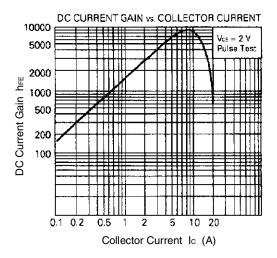


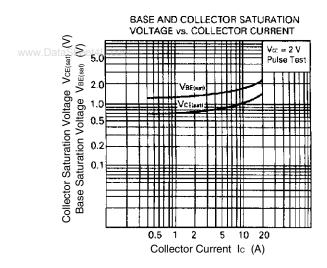




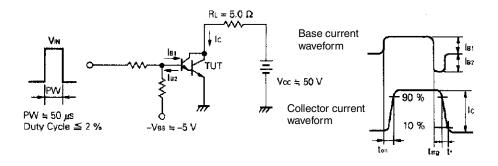








SWITCHING TIME (ton, tstg, tf) TEST CIRCUIT



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